

Search Notes

Application/Control No.

10/692,773

Examiner

Eric B. Chen

Applicant(s)/Patent under
Reexamination

LEE, HEON

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	18,22,38	6/16/2005	EC
216	39,46,67	6/16/2005	EC
216	3,257	6/16/2005	EC
216	104,107	6/16/2005	EC
216	109	6/16/2005	EC
438	692,696	6/16/2005	EC
438	710,723	6/16/2005	EC
438	724,725	6/16/2005	EC
438	745,756	6/16/2005	EC
438	757	6/16/2005	EC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Performed inventor search for double patenting	6/16/2005	EC
EAST search	6/16/2005	EC